

<b>Notice of References Cited</b>	Application/Control No. 10/658,228		Applicant(s)/Patent Under Reexamination CHEN, YUN-LUNG	
	Examiner Hanh V. Tran		Art Unit 3637	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,660,297 A	08-1997	Liu, Morgan C.	220/4.02
*	B	US-5,896,273 A	04-1999	Varghese et al.	361/724
*	C	US-6,038,892 A	03-2000	Schmitt, Ty. R.	292/303
*	D	US-6,373,690 B1	04-2002	Buican et al.	361/683
*	E	US-6,478,392 B2	11-2002	Gan et al.	312/223.2
*	F	US-2002/0185944 A1	12-2002	Chen, Feng-Ming	312/223.2
*	G	US-6,535,379 B1	03-2003	Smeenge et al.	361/724
*	H	US-6,530,628 B1	03-2003	Huang et al.	312/223.2
*	I	US-6,529,371 B1	03-2003	Laio, Nien Chiang	312/223.2
*	J	US-6,555,747 B2	04-2003	Chen et al.	312/223.2
*	K	US-6,738,255 B2	05-2004	Chen, Yun-Lung	312/223.2
*	L	US-6,903,933 B2	06-2005	Wang, Ching-Wen	312/223.2
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	04099094	03-1992	Japan	Hirata	361/724
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.